

# MicroXCT-400 High Resolution 3D X-ray Imaging System

## Applications and Specifications



**3D resolution to <math><1.0\ \mu\text{m}</math> pixel**  
**Sample sizes to 100 mm**



The Xradia MicroXCT-400 also supports in-situ experiments such as tensile/ compression and temperature variation tests while imaging. It delivers superior flexibility with a four-door fully accessible sample stage, supplying sample sizes up to 100 mm.

### Key benefits

- High resolution X-ray 3D full volume imaging
- High contrast phase enhanced imaging
- Broad sample size and weight capability to 15 kg
- Non destructive imaging of samples
- Accelerated understanding of internal structure complexity

### Overview

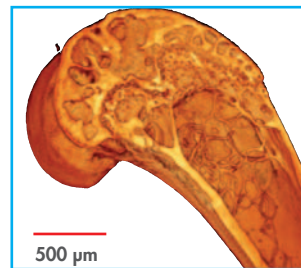
The Xradia MicroXCT-400 is a new class of 3D X-ray imaging solution optimized for non-destructive imaging of complex internal structures. It enables accelerated, highly efficient analysis of structures examined in a variety of applications:

- Semiconductor packaging development and failure analysis
- Life-science research
- Rock microstructure modeling for oil and gas exploration
- Advanced material characterization
- In situ measurement during imaging

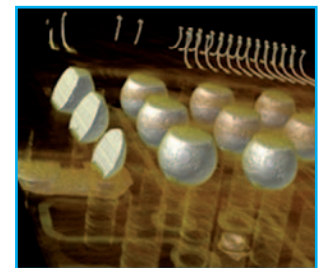
The Xradia MicroXCT-400 provides the unique ability to reveal the internal structure with full 3D imaging of features down to <math><1.0</math> micron resolution, making it a compelling alternative for research and the inspection and control of manufacturing processes.

### Applications

The system provides a view into deeply buried micro structures that may be unobservable with current 2D surface imaging techniques such as optical microscopy, SEM and AFM. In addition, it enables ultra-fine analysis of the structure in a variety of applications. For instance, visualizing osteocyte lacunae in bone morphology; micro-cracks and voids in composite materials; defects such as BGA cracks in semiconductor package, and micro pores in rocks.



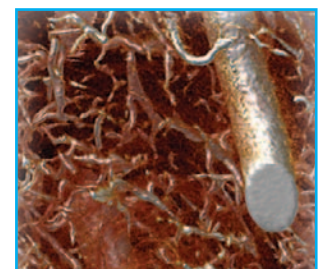
Rat Knee



Solder Balls and Wires



Grain of Sand



Bovine Cerebral Tissue

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### System

Resolution & detector area			
Detectors	Resolution at 10% MTF <sup>1</sup> [μm]	Pixel size [μm]	Sample width limit [mm]
Macro-70	16	7	100
2X	5	2	100
4X	3.3	1	100
10X	2.5	0.7	100
20X	1.5	0.5	20
40X	<1μ	0.3	20

<sup>1</sup> MTF measured using Xradia's standard 2D resolution target.

### Components

Stages				
Sample stage <sup>2</sup>	X-axis	Y-axis	Z-axis	Rotation
Travel	45 mm	100 mm	50 mm	360 °
Load capacity	15 kg			

<sup>2</sup> The system Z direction is defined to be along the X-ray beam path and system Y direction is defined as the vertical axis.

Source & detector axes		
	Source	Detector
Travel	400 mm	400 mm

Source		
Source type	150 kV	90 kV
Max. voltage	150 kV	90 kV
Min. voltage	40 kV	40 kV
Max. power	10 W	8 W

All specifications subject to change.